

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS2180A	Nov-96	9642 B3	ANAM, K.	DN634588AAA1	2.0μ OXIDE	44 PLCC

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-18598

<u>Electrical</u>	<u>Cum %</u>
235/0	0.0%

Sonoscan
P-18641

<u>Post Vapor Phase</u>
4/0

Infant / High Voltage Life
125°C, 7.0 V.
P-18642, P-18705

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>
231/1	77/0	
F1		

*Failure Rate

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-18706

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
49/0		

Biased Moisture (HAST)
121°C/85% RH, 5.5 V.
P-18707

<u>100 Hr</u>	<u>Cum %</u>
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Autoclave
121°C/100% RH, 2 Atmos
P-18708

<u>96 Hr</u>	<u>Cum %</u>
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Failure Mode
F1: IVDD

Failure Analysis
In process, 970016